

United States Patent [19]

Ide et al.

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[45] Date of Patent: **** Oct. 30, 1990**

[54] **ELECTRONIC THERMOMETER PROBE**

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[73] Assignee: **Terumo Kabushiki Kaisha, Tokyo, Japan**

[**] Term: **14 Years**

[21] Appl. No.: **152,579**

[22] Filed: **Feb. 5, 1988**

[30] **Foreign Application Priority Data**

Oct. 21, 1987 [JP] Japan 62-42746

[52] U.S. Cl. **D10/60**

[58] Field of Search D10/57, 60; 374/100, 374/106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209; 128/736, 207.14

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[57] **CLAIM**

The ornamental design for an electronic thermometer, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of an electronic thermometer probe showing our new design;
FIG. 2 is a top plan view, the bottom plan view being identical;
FIG. 3 is a rear elevational view;
FIG. 4 is a left side elevational view;
FIG. 5 is a right side elevational view; and
FIG. 6 is a cross-sectional view taken along line 6—6 of FIG. 1 thereof.

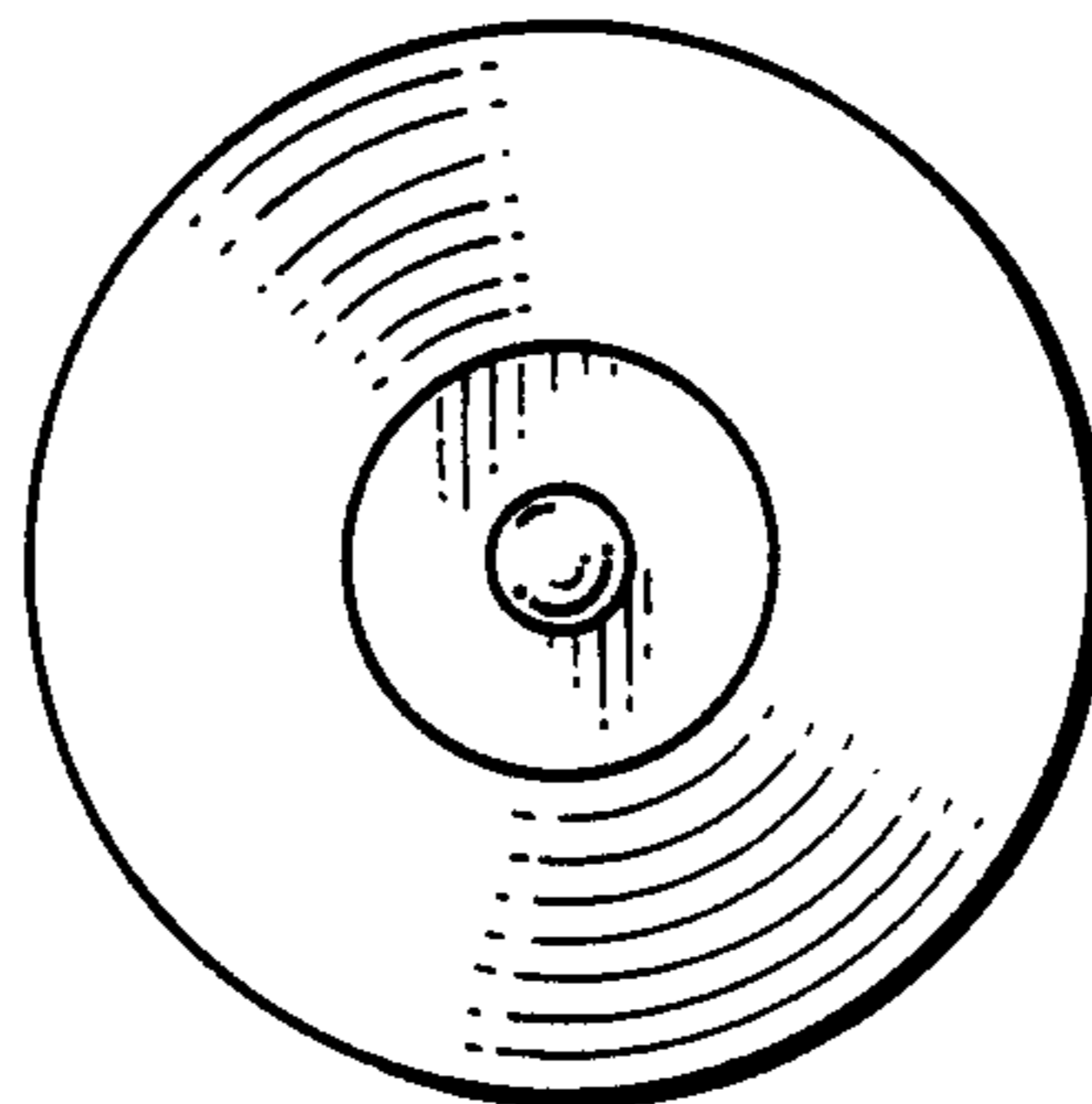


FIG. 1

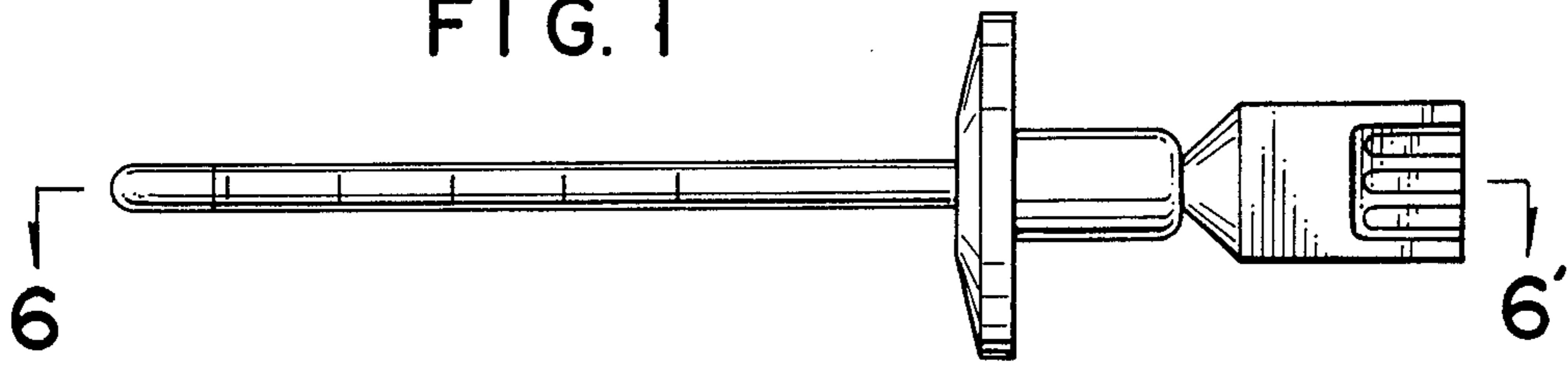


FIG. 2

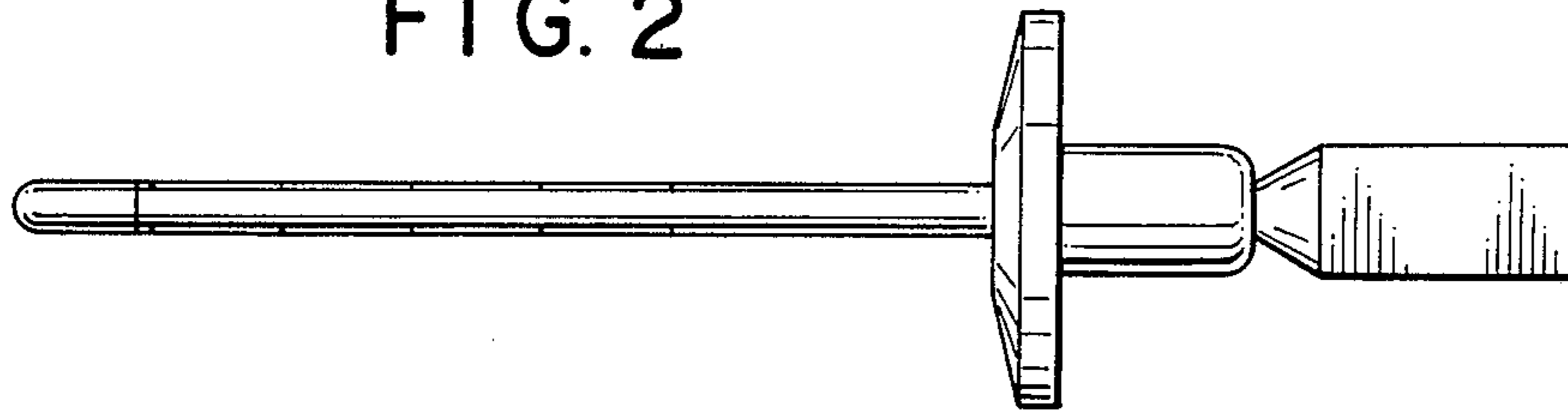


FIG. 3

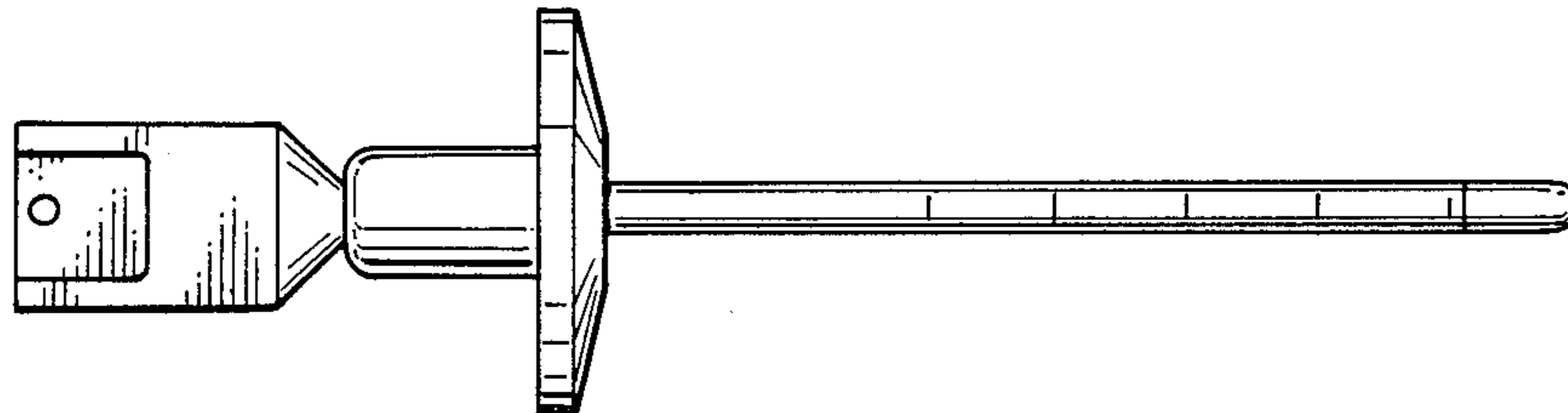


FIG. 4

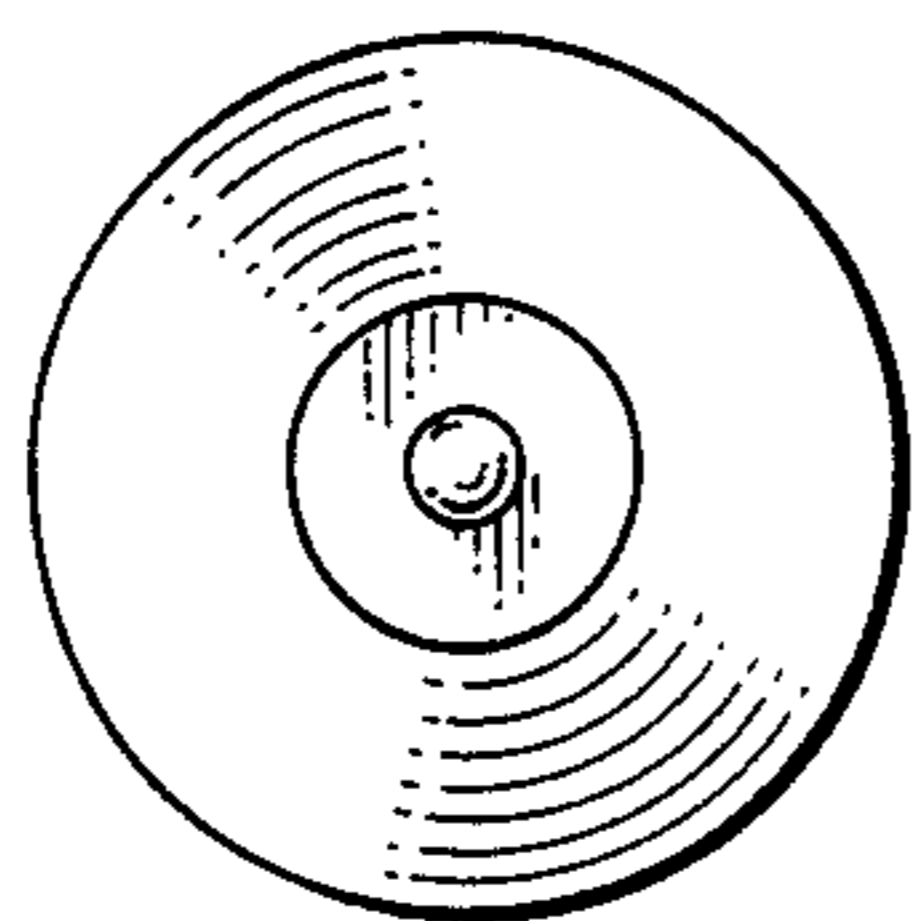


FIG. 5

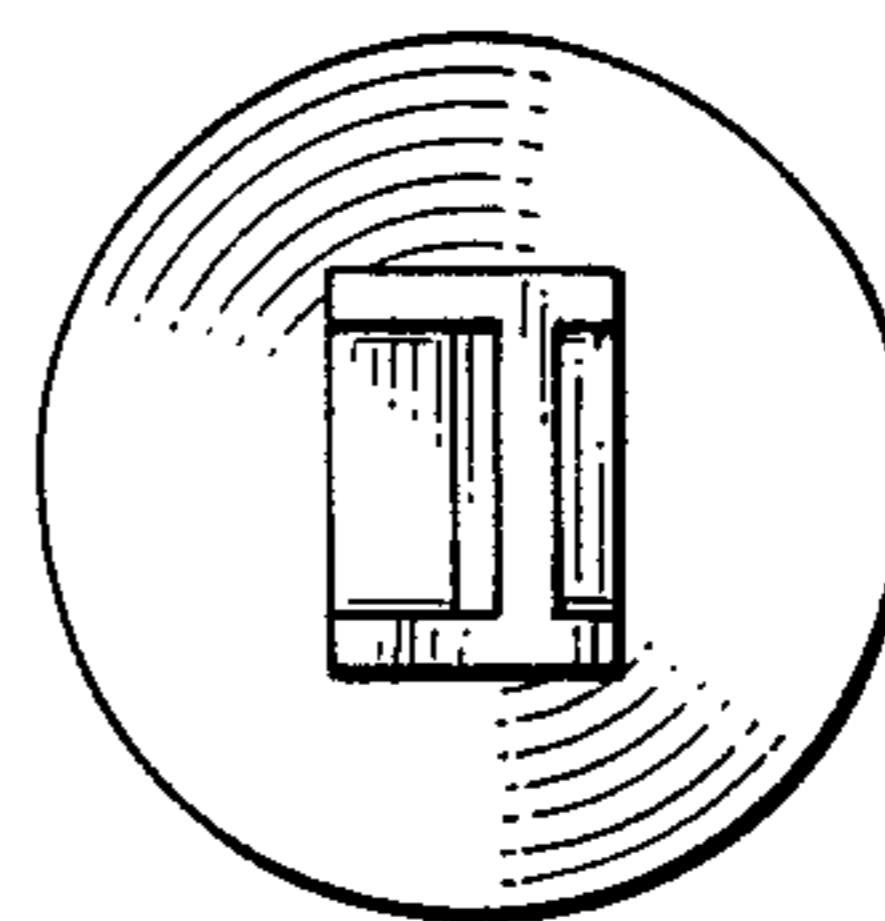


FIG. 6

